

# 近場光學顯微分光光譜儀/橢圓儀

## Near-field Optical Spectrometers / Ellipsometers

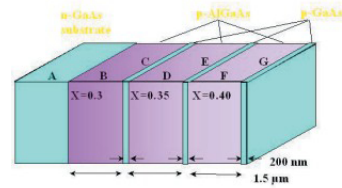
NFS-100 / 200 / 300 研究奈米科技的最佳利器

New

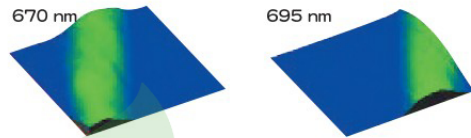


- 利用近場光 (Near-Field Light) 可偵測反射、螢光、拉曼等多種光譜
- 突破光學限制, 探針光圈可小至 100 nm 以下
- 回饋式顯微探針, 可接近至樣品表面 30 nm 高度, 配合 Mapping 系統同時獲得樣品表面結構圖像 (Topography)
- 可擴充液態氮冷卻裝置進行超低溫 (6°K) 測量

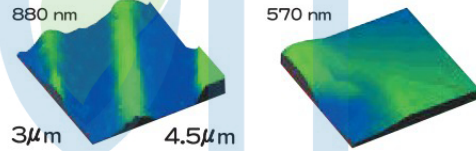
光學元件之近場光譜分析



- pAlGaAs -



- pGaAs -



### M-200 / 300 / 500 橢圓儀



### 特點：

- Stable and Reliable
- Patented Optical Servo
- Solid State PEM Optics
- Maximum Sensitivity
- Multiple Light Sources
- User Replaceable Stage blocks

其他機型：M-300, M-500

### 應用：

- Liquid-crystal display time-resolved measurements
- Semiconductor materials characterization
- Opto-magnetic and optical storage media like  $\text{Ge}_2\text{Sb}_2\text{Te}_5$  for DVD
- Poly-silicon, amorphous silicon for solar cells
- Silicon-on-insulator (SOI) buried-layer measurements
- Metals and ceramic thin-layers like  $\text{TiN}$ ,  $\text{AlO}_x$ ,  $\text{WSi}_x$
- Photo-resist coatings and polymer layers
- Coatings for optical components including laser mirrors
- Materials science studies such as Langmuir-Boldgett films, DLC, dielectrics
- Biological science applications including molecular monolayers and membranes